# AT27C516

#### Features

- Fast Read Access Time 45 ns .
- Low Power CMOS Operation 100 µA max. Standby 30 mA max. Active at 5 MHz
- JEDEC Standard Packages 44-Lead PLCC 40-Lead TSOP (10mm x 14mm)
- $5V \pm 10\%$  Power Supply
- High Reliability CMOS Technology • 2000V ESD Protection 200 mA Latchup Immunity
- Rapid<sup>™</sup> Programming Algorithm 50 µs/word (typical) •
- **CMOS and TTL Compatible Inputs and Outputs** •
- Integrated Product Identification Code •
- **Commercial and Industrial Temperature Ranges**

## Description

The AT27C516 is a low-power, high performance 524,288 bit one-time programmable read only memory (OTP EPROM) organized 32K by 16 bits. It requires only one 5V power supply in normal read mode operation. Any word can be accessed in less than 45 ns, eliminating the need for speed reducing WAIT states. The by-16 organization make this part ideal for high-performance 16 and 32 bit microprocessor systems. (continued)

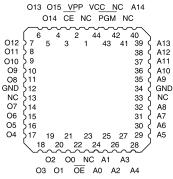
# 512K (32K x 16) **OTP CMOS EPROM**

## Pin Configurations

Pin Name	Function
A0 - A14	Addresses
O0 - O15	Outputs
CE	Chip Enable
OE	Output Enable
PGM	Program Strobe
NC	No Connect

Note: Both GND pins must be connected.

#### PLCC Top View



Note: PLCC Package Pins 1 and 23 are DON'T CONNECT.

#### **TSOP** Top View Type 1

A9 A10	$\bigcirc$ 1 <sub>2</sub>	<sup>40</sup> 39	-  -   A8	GND
A11 9	3	38	P	A7
A12 G	4 5	36 <sup>37</sup>	A6	A5
NC A14	6 7	35 34	A4	A3
NC 🗆	8 0	33 32	E A2	
	9 10	31	F AO	A1
	11 12	<sup>30</sup> 29	Εoo	OE
015 014	14 <sup>13</sup>	28 23 27		01
012 0	15	26	Ь	O3
	10	25	6 04	05
	10	23	E 06	
<sup>O9</sup> O8	20 <sup>19</sup>	<sup>22</sup> 21	☐ GND	07



3-145



## **Description** (Continued)

In read mode, the AT27C516 typically consumes 15 mA. Standby mode supply current is typically less than 10  $\mu A.$ 

The AT27C516 is available in industry standard JEDEC-approved one-time programmable (OTP) plastic PLCC and TSOP packages. The device features two-line control (CE, OE) to eliminate bus contention in high-speed systems.

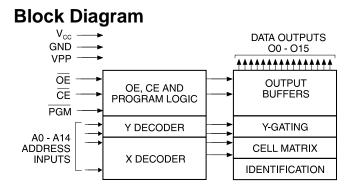
With 32K word storage capability, the AT27C516 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's 27C516 have additional features to ensure high quality and efficient production use. The Rapid<sup>™</sup> Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 50 μs/word. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.

## **System Considerations**

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed data sheet limits, resulting in device non-conformance. At a minimum, a 0.1  $\mu$ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V<sub>CC</sub> and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7  $\mu$ F bulk electrolytic capacitor should be utilized, again connected between the V<sub>CC</sub> and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

AT27C516



#### **Absolute Maximum Ratings\***

Temperature Under Bias55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground2.0V to +7.0V <sup>(1)</sup>
Voltage on A9 with Respect to Ground2.0V to +14.0V <sup>(1)</sup>
VPP Supply Voltage with Respect to Ground2.0V to +14.0V $^{(1)}$

\*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V dc which may undershoot to - 2.0V for pulses of less than 20 ns. Maximum output pin voltage is  $V_{CC}$  + 0.75V dc which may overshoot to +7.0V for pulses of less than 20 ns.

## **Operating Modes**

Mode \ Pin	CE	OE	PGM	Ai	Vpp	Outputs
Read	VIL	VIL	X <sup>(1)</sup>	Ai	Х	Dout
Output Disable	Х	VIH	Х	Х	Х	High Z
Standby	VIH	Х	Х	Х	X <sup>(5)</sup>	High Z
Rapid Program <sup>(2)</sup>	VIL	VIH	VIL	Ai	Vpp	DIN
PGM Verify	VIL	VIL	VIH	Ai	Vpp	Dout
PGM Inhibit	VIH	Х	Х	Х	VPP	High Z
Product Identification <sup>(4)</sup>	VIL	VIL	Х	A9 = V <sub>H</sub> <sup>(3)</sup> A0 = V <sub>I</sub> H or V <sub>I</sub> L A1 - A14 = V <sub>I</sub> L	Vcc	Identification Code

Notes: 1. X can be  $V_{IL}$  or  $V_{IH}$ .

2. Refer to Programming characteristics.

3.  $V_H = 12.0 \pm 0.5 V$ .

4. Two identifier words may be selected. All Ai inputs are held low (V<sub>IL</sub>), except A9 which is set to V<sub>H</sub> and A0 which is toggled low (V<sub>IL</sub>) to select the Manufacturer's Identification word and high (V<sub>I</sub>) to select the Device Code word.

Standby V<sub>CC</sub> current (I<sub>SB</sub>) is specified with V<sub>PP</sub> = V<sub>CC</sub>. V<sub>CC</sub> > V<sub>PP</sub> will cause a slight increase in I<sub>SB</sub>.





## DC and AC Operating Conditions for Read Operation

				AT27C516		
		-45	-55	-70	-85	-10
Operating	Com.	0°C - 70°C	0°C - 70°C	0°C - 70°C	0°C - 70°C	0°C - 70°C
Temperature (Case)	Ind.	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C
V <sub>CC</sub> Power Supply		$5V \pm 10\%$	$5V \pm 10\%$	$5V \pm 10\%$	5V ± 10%	5V ± 10%

## **DC and Operating Characteristics for Read Operation**

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to $V_{CC}$		± 1	μA
ILO	Output Leakage Current	$V_{OUT} = 0V$ to $V_{CC}$		±5	μA
I <sub>PP1</sub> <sup>(2)</sup>	V <sub>PP</sub> <sup>(1)</sup> Read/Standby Current	VPP = VCC		10	μA
I <sub>SB</sub>	V <sub>CC</sub> <sup>(1)</sup> Standby Current	I <sub>SB1</sub> (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μΑ
128		$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC}$ + 0.5V		1	mA
lcc	V <sub>CC</sub> Active Current	f = 5 MHz, $I_{OUT}$ = 0 mA, $\overline{CE}$ = V <sub>IL</sub>		30	mA
VIL	Input Low Voltage		-0.6	0.8	V
Vін	Input High Voltage		2.0	Vcc + 0.5	V
V <sub>OL</sub>	Output Low Voltage	l <sub>OL</sub> = 2.1 mA		0.4	V
Vон	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V

Notes: 1.  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$ , and removed simultaneously or after  $V_{PP}$ .

 V<sub>PP</sub> may be connected directly to V<sub>CC</sub>, except during programming. The supply current would then be the sum of I<sub>CC</sub> and I<sub>PP</sub>.

## **AC Characteristics for Read Operation**

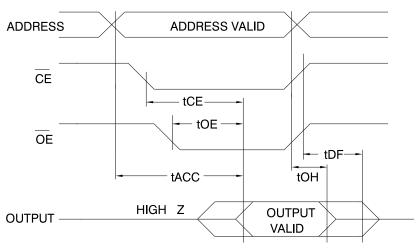
				AT27C516									
			-4	45	-{	55	-7	70	-8	35	-^	10	
Symbol	Parameter	Condition	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Units
tACC <sup>(3)</sup>	Address to Output Delay	$\overline{CE} = \overline{OE} = VIL$		45		55		70		85		100	ns
t <sub>CE</sub> <sup>(2)</sup>	CE to Output Delay	$\overline{OE} = V_{IL}$		45		55		70		85		100	ns
t <sub>OE</sub> (2, 3)	OE to Output Delay	$\overline{CE} = V_{IL}$		20		25		25		30		30	ns
tDF <sup>(4, 5)</sup>	OE or CE High to Output Fl whichever occurred first	oat,		20		25		25		30		30	ns
tон	Output Hold from Address, CE or OE, whichever occurred first		7		7		7		0		0		ns

Notes: 2, 3, 4, 5. - see AC Waveforms for Read Operation.

3-148

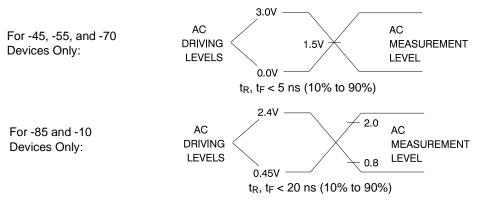
AT27C516

## AC Waveforms for Read Operation <sup>(1)</sup>



- Notes: 1. Timing measurement reference level is 1.5V for -45 and -55 devices. Input AC drive levels are  $V_{IL} =$ 0.0V and  $V_{IH} = 3.0V$ . Timing measurement reference levels for all other speed grades are  $V_{OL}$ = 0.8V and  $V_{OH} = 2.0V$ . Input AC drive levels are  $V_{IL} = 0.45V$  and  $V_{IH} = 2.4V$ .
  - OE may be delayed up to t<sub>CE</sub> t<sub>OE</sub> after the falling edge of CE without impact on t<sub>CE</sub>.
- OE may be delayed up to t<sub>ACC</sub> t<sub>OE</sub> after the address is valid without impact on t<sub>ACC</sub>.
- 4. This parameter is only sampled and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

## Input Test Waveforms and Measurement Levels



# Output Test Load

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Note: CL = 100 pF including jig capacitance except -45, -55 and -70 devices, where CL = 30 pF.

## **Pin Capacitance** $(f = 1 \text{ MHz } T = 25^{\circ}\text{C})^{(1)}$

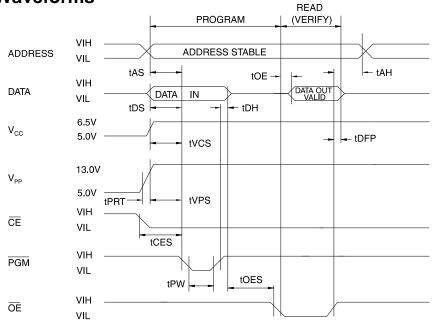
	Тур	Max	Units	Conditions	
CIN	4	10	pF	$V_{IN} = 0V$	
COUT	8	12	pF	$V_{OUT} = 0V$	

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.





## **Programming Waveforms**<sup>(1)</sup>



- Notes: 1. The Input Timing Reference is 0.8V for  $V_{IL} \label{eq:VI}$  and 2.0V for  $V_{IH}.$ 
  - 2.  $t_{\mbox{\scriptsize OE}}$  and  $t_{\mbox{\scriptsize DFP}}$  are characteristics of the device but must be accommodated by the programmer.
- 3. When programming the AT27C516 a 0.1  $\mu F$  capacitor is required across  $V_{PP}$  and ground to suppress spurious voltage transients.

## **DC Programming Characteristics**

#### $T_{\text{A}}$ = 25 $\pm$ 5°C, $V_{\text{CC}}$ = 6.5 $\pm$ 0.25V, $V_{\text{PP}}$ = 13.0 $\pm$ 0.25V

		Test	L		
Symbol	Parameter	Conditions	Min	Max	Units
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA
VIL	Input Low Level		-0.6	0.8	V
VIH	Input High Level		2.0	V <sub>CC</sub> + 0.1	V
Vol	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
Vон	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V
ICC2	V <sub>CC</sub> Supply Current (Program and Verify)			50	mA
IPP2	VPP Supply Current	$\overline{CE} = \overline{PGM} = V_{IL}$		30	mA
VID	A9 Product Identification Voltage		11.5	12.5	V

## AT27C516

## **AC Programming Characteristics**

 $T_{\text{A}}$  = 25  $\pm$  5°C,  $V_{\text{CC}}$  = 6.5  $\pm$  0.25V,  $V_{\text{PP}}$  = 13.0  $\pm$  0.25V

Sym-	Test	Li	mit	
bol	Parameter Conditions* (1)	Min	Max	Units
tAS	Address Setup Time	2		μS
tCES	CE Setup Time	2		μS
toes	OE Setup Time	2		μS
t <sub>DS</sub>	Data Setup Time	2		μS
tан	Address Hold Time	0		μS
tDH	Data Hold Time	2		μS
tDFP	OE High to Output Float Delay <sup>(2)</sup>	0	130	ns
tvps	VPP Setup Time	2		μS
tvcs	V <sub>CC</sub> Setup Time	2		μS
tpw	<b>PGM</b> Program Pulse Width <sup>(3)</sup>	47.5	52.5	μS
toE	Data Valid from OE		150	ns
tPRT	VPP Pulse Rise Time During Programming	50		ns

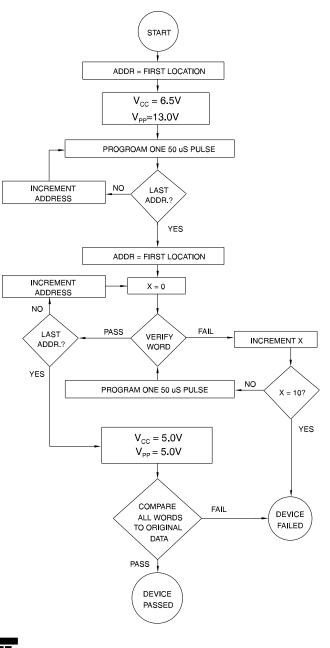
\*AC Conditions of Test:

Input Rise and Fall Times (10% to 90%)......20 ns Input Pulse Levels.....0.45V to 2.4V Input Timing Reference Level.....0.8V to 2.0V Output Timing Reference Level.....0.8V to 2.0V

- Notes: 1. V<sub>CC</sub> must be applied simultaneously or before V<sub>PP</sub> and removed simultaneously or after V<sub>PP</sub>.
  - This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven — see timing diagram.
  - 3. Program Pulse width tolerance is 50  $\mu \text{sec} \pm 5\%.$

## **Rapid Programming Algorithm**

A 50  $\mu$ s PGM pulse width is used to program. The address is set to the first location. V<sub>CC</sub> is raised to 6.5V and V<sub>PP</sub> is raised to 13.0V. Each address is first programmed with one 50  $\mu$ s PGM pulse without verification. Then a verification / reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 50  $\mu$ s pulses are applied with a verification after each pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked. V<sub>PP</sub> is then lowered to 5.0V and V<sub>CC</sub> to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.



#### Atmel's 27C516 Integrated Product Identification Code

		Pins						Hex			
Codes	A0	015-08	07	06	O5	04	О3	02	01	O0	Data
Manufacturer	0	0	0	0	0	1	1	1	1	0	001E
Device Type	1	0	1	1	1	1	0	0	1	0	00F2



## **Ordering Information**

tacc	lcc	(mA)	Ordering Code	Dealraga	Operation Benge	
(ns)	Active	Standby	Ordering Code	Package	Operation Range	
45	30	30 0.1 AT27C516-45JC AT27C516-45VC		44J 40V	Commercial (0°C to 70°C)	
	30	0.1	AT27C516-45JI AT27C516-45VI	44J 40V	Industrial (-40°C to 85°C)	
55	30	0.1	AT27C516-55JC AT27C516-55VC	44J 40V	Commercial (0°C to 70°C)	
	30	0.1	0.1 AT27C516-55JI 44J AT27C516-55VI 40V		Industrial (-40°C to 85°C)	
70	30	0.1	AT27C516-70JC AT27C516-70VC	44J 40V	Commercial (0°C to 70°C)	
	30	0.1	AT27C516-70JI AT27C516-70VI	44J 40V	Industrial (-40°C to 85°C)	
85	30	0.1	AT27C516-85JC AT27C516-85VC	44J 40V	Commercial (0°C to 70°C)	
	30	0.1	AT27C516-85JI AT27C516-85VI	44J 40V	Industrial (-40°C to 85°C)	
100	100 30 0.1   30 0.1		AT27C516-10JC AT27C516-10VC	44J 40V	Commercial (0°C to 70°C)	
			AT27C516-10JI AT27C516-10VI	44J 40V	Industrial (-40°C to 85°C)	

Package Type	
44J	44 Lead, Plastic J-Leaded Chip Carrier (PLCC)
40V	40 Lead, Plastic Thin Small Outline Package (TSOP) (10mm x 14mm)

# AT27C516